

**Search Notes**

Application/Control No.

10/032,729

Examiner

John L. Shew

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	347,352	4/24/2006	JS
	363,367		
	368,371		
	378,379		
	381,389		
	390,395,3		
	412,428		
	429		
708	232,273	4/24/2006	JS
709	230,236	4/24/2006	JS
Class 709	238,243 Subclass 1	Date 4/24/2006	Examiner
	250		
710	310	4/24/2006	JS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
708	232,273	4/24/2006	JS

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
10/032,729	CHEN ET AL.	Art Unit 2616
4/24/2006	2006	
SEARCHING Strategy	Examiner	EXMR